


<b>Search Notes</b>  	<b>Application/Control No.</b>  10550324	<b>Applicant(s)/Patent Under Reexamination</b>  TACHIKAWA ET AL.
	<b>Examiner</b>  Christopher L Chin	<b>Art Unit</b>  1641

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
EAST search	3/30/08	CC
STN-CAS search	3/30/08	CC
EAST search	11/5/08	CC
EAST and STN-CAS search	6/20/09	CC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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